Open Networking Testing Service
Open Network Systems Interoperability Test Report

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Enclosed are the results from the Open Network Systems Interoperability performed on:

Module or Cable Assembly Under Test (MUT/CUT):

Vendor and Device Type	10Gtek SFP+
Part Number	AXS13-192-10

Host Under Test (HUT):

Host System 1 Composition	
Network Operating System	Cumulus
OS Version	3.4
Bare Metal Switch	Accton AS5712
Part Number	5712
ONIE Version	2018.02

This testing pertains to the Open Network Systems Interoperability Test Plan, which outlines a series of tests performed on a variety of optical transceivers and cables with bare-metal open switches running Network Operating Systems from multiple vendors. The focus of these tests was basic interoperability, which aims to validate the operation of open network systems.

As always, we welcome any comments regarding this Test Suite. If you have any questions about the test procedures or results, please feel free to contact me via e-mail at david@iol.unh.edu or by phone at +1-603-862-0090.

Regards,
David Woolf

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In section 2, the following equipment was used:

Test System Hardware	
EEPROM Reader	I2C Elite Reader

In section 3, the following equipment was used:

Test System Hardware	
Network Analyzer	PNA –Performance Network Analyzer

In section 4, the following equipment was used:

| Test System Hardware	
Wide Bandwidth Oscilloscope	Keysight DCA-X 86100D Wide Bandwidth Oscilloscope
Waveform Analyzer	Keysight 86105C Optical Waveform Analyzer
50GHz Waveform Analyzer	Keysight 86108B Mega Module, 50GHz Bandwidth Waveform Analyzer
Clock Recovery Module	Keysight 83496B Optical/Electrical Clock Data Recovery Unit
High Performance Serial BERT	Tektronix BERTScope
Signal Quality Analyzer	BERTScope PRBS9 at 10.3125Gbps
De-Emphasis Signal Converter	Agilent N4916B

*Two modules used during testing

In section 6, an Ostinato was used to generate test traffic:

Test System Hardware	
Ethernet Traffic Generator	10Gb Ethernet Network Adapter Card
Software Version	Ostinato
Port Types	10G SFP, 40G QSFP

The following table contains possible results and their meanings.

Result	Interpretation
PASS	The Device Under Test (DUT) was observed to exhibit conformant behavior.
PASS W/ Comments	The specified behavior is demonstrated by the DUT; however, this result indicates that either changes were made to the standard test procedure or results other than the expected results were observed.
FAIL	The DUT was observed to exhibit non-compliant behavior.
INFO	This Test is designed for informational purposes only. While the results may help ensure the interoperability of the DUT, a PASS/FAIL is not given for this test.
WARN	The DUT was observed to exhibit behavior that is not recommended.
N/A	Not Applicable. This test is not applicable for the DUT.
N/S	Not Supported. This test was not run due to features not implemented on the DUT.
N/T	Not tested. This test was not run.
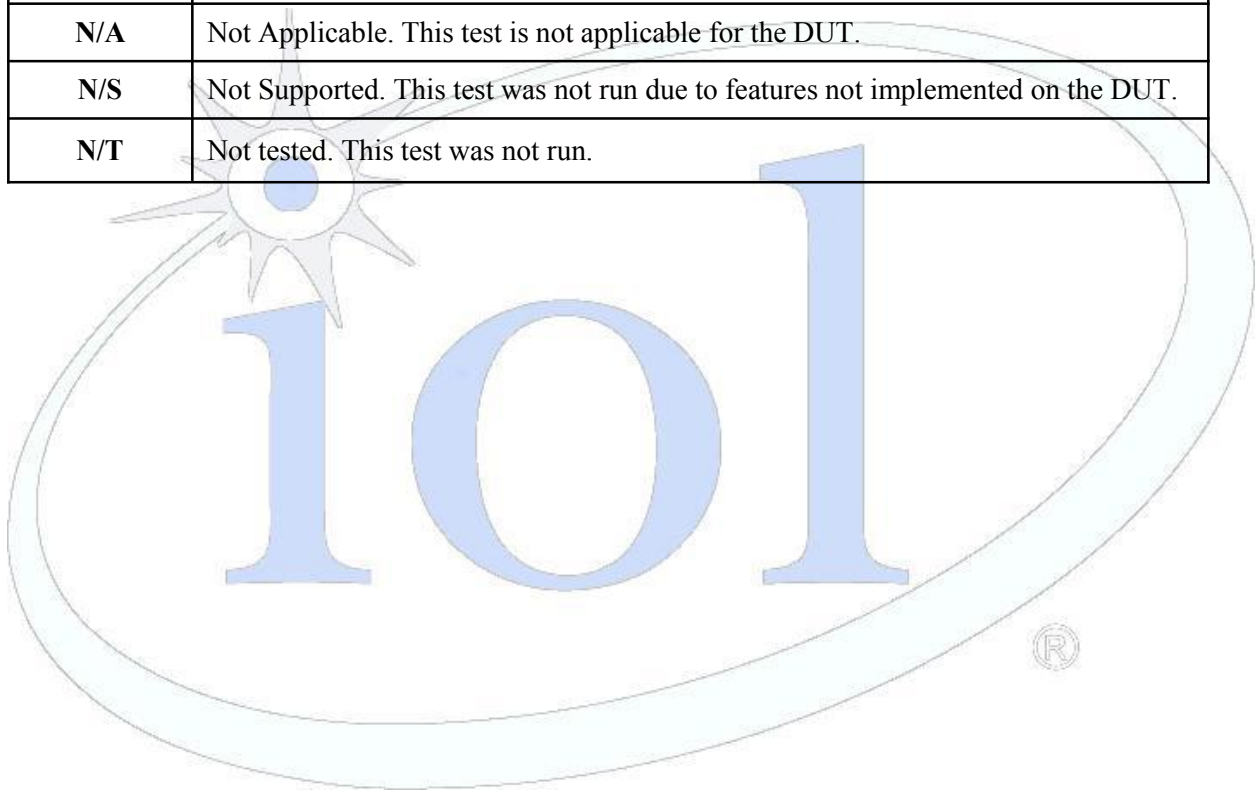
Summary of Results- Conformance	
Test	**Result**
Test 1.1: ONIE Compliance Environment	**N/A**
Test 1.2: Installing and uninstalling a NOS through ONIE via HTTP server	**PASS**
Test 3.1.1: Return Loss for 10G Passive Cable	**PASS**
Test 3.1.2: Insertion Loss for 10G Passive Cable	**PASS**
Test 5.1.1: Output Rise and Fall Times for 100G Host	**PASS**
Test 5.1.2: Transmitter Eye Mask for 100G Host	**PASS**
Test 5.1.3: Total Jitter for 100G Host	**PASS**
Test 5.1.4: Input and Output Return Loss on 100G Host	**PASS**

Summary of Results - Interoperability	
Test	**Result**
Test 2.1: Physical Compatibility with Supporting Devices	**PASS**
Test 2.2: Host Management of Module or Cable Assembly	**PASS**
Test 2.3: Diagnostic Optical Monitor Support	**PASS**
Test 6.1: Establish Baseline Performance Analysis	**PASS**
Test 6.2: Link Detection on Power Up	**PASS**
Test 6.3: Packet Error Rate Estimation	**PASS**
Test 6.4: Packet Loss/Stress Test	**PASS**

Notes

Conformance Test Results	
Test Information	**Test Result**
Test 1.1: **ONIE Compliance Environment** *Purpose*: To verify that a host can pass a random sampling of ONIE Compliance Environment tests.	**N/A**
Comments on Test Procedure	
The random sampling of tests from the ONIE Compliance Environment was not used.	
Comments on Test Results	
Additional Comments	
This test is only applicable to Hosts which have not performed ONIE compliance testing previously.	

Test Information	Test Result
Test 1.2: **Installing and uninstalling a NOS through ONIE via HTTP server** *Purpose*: To verify that a NOS can be successfully installed through ONIE.	**PASS**
Comments on Test Procedure	
This test was completed using the standard procedure as written in the Test Plan. The random sampling of tests from the ONIE Compliance Environment was not used.	
Comments on Test Results	
Part A: The DUT was able to install the NOS via ONIE. **Part B:** The DUT was able to uninstall the NOS via ONIE.	
Additional Comments	

Test Information	Test Result
Test 3.1.1: **Return loss for 10G Passive Cable** *Purpose*: To verify that the return loss of the DUT is within the conformance limits provided by SFF-8431 Appendix E, Table 37.	**PASS**
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
The differential return loss observed did not violate the limits governed by SFF-8431 Appendix E.4, Table 37 for 10GBASE-CR passive cables:	
Additional Comments	

Test Information	Test Result
Test 3.1.2: **Insertion Loss for 10G Passive Cable** *Purpose*: To verify that the insertion loss of the Cable under test is within the conformance limits provided by IEEE Std. 802.3-2012 Annex, Table 37.	**PASS**
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
The insertion loss of the cable under test does not violate the requirements passive cable assemblies.	
Additional Comments	

Test Information	Test Result
Test 5.1.1: **Output Rise and Fall Times for 10G Host** *Purpose*: To verify that the Eye Mask Hit Ratio is within the conformance limits.	**PASS**
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
The device under test exhibited the expected behavior.	
Additional Comments	

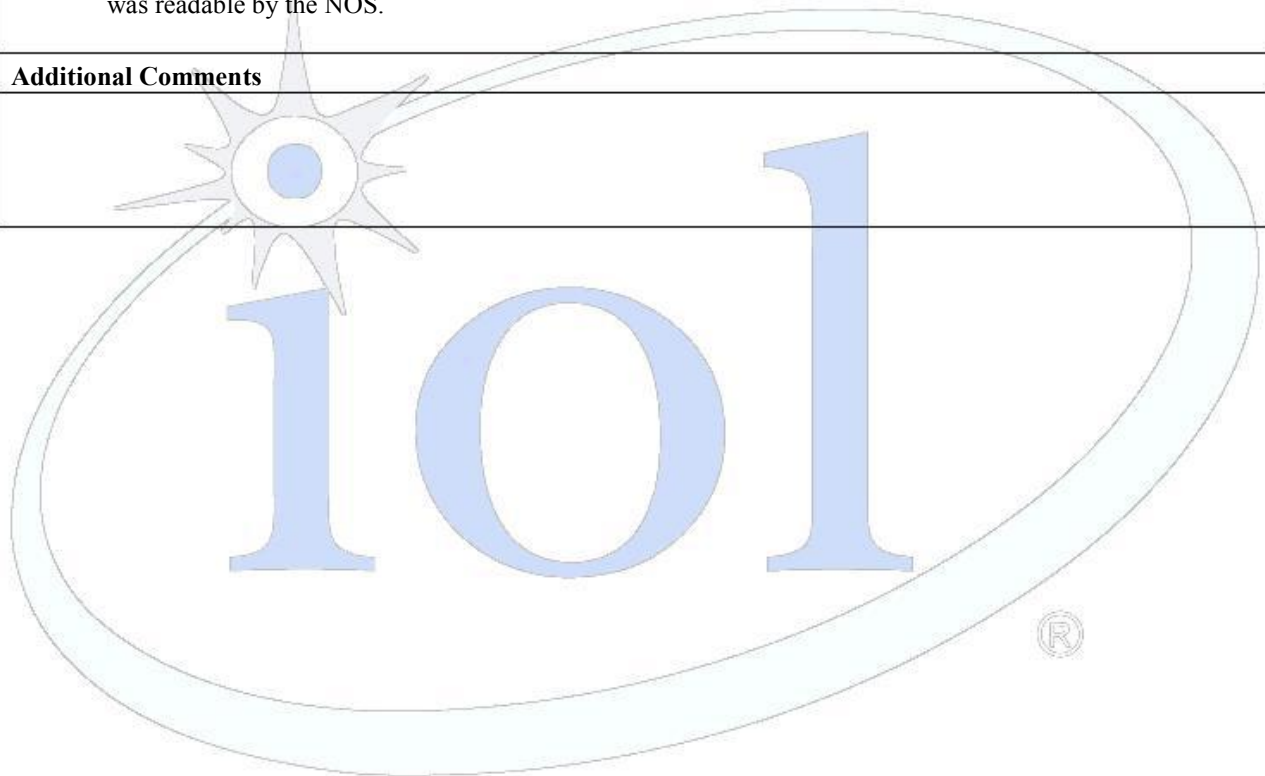| Test Information	Test Result
Test 5.1.2: **Transmitter Eye Mask on 10G Host** *Purpose*: To verify that the Eye Mask Hit Ratio is within the conformance limits.	**PASS**
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
The device under test exhibited the expected behavior.	
Additional Comments	

Test Information	Test Result
Test 5.1.3: **Total Jitter for 10G Host** *Purpose*: To verify that the Total Jitter (TJ) is within the conformance limit.	**PASS**

Comments on Test Procedure
The test was completed with the standard procedure.

Comments on Test Results
The device under test exhibited the expected behavior.

Additional Comments

Test Information	Test Result
Test 5.1.4: **Input and Output Return Loss on 10G Host** *Purpose*: To verify that the differential input and output return loss of the DUT is within conformance limits.	**PASS**

Comments on Test Procedure
The test was completed with the standard procedure.

Comments on Test Results
The device under test exhibited the expected behavior.

Additional Comments
See Appendix B

Interoperability Test Results	
Test Information	**Test Result**
Test 2.1: **Physical Compatibility with Supporting Devices** *Purpose*: To verify that the mechanical form factor is compatible with devices for interoperability purposes.	**PASS**
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
Part A: The MUT/CUT was able to be inserted into the Host. **Part B:** This test is not applicable to Cable Assemblies. **Part C:** The MUT/CUT was able to be removed from the Host.	
Additional Comments	

Test Information	**Test Result**
Test 2.2: **Host Management of Module or Cable Assembly** *Purpose*: To verify that the MUT/CUT is manageable via the Host complex.	**PASS**
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
Part B: The EEPROM data of the MUT/CUT was readable. The serial number and vendor information extracted from the EEPROM data matches the serial number and vendor information of the part.	
Additional Comments	

Test Information	Test Result
Test 2.3: **Diagnostic Optical Monitor Support** *Purpose*: To verify that the MUT/CUT (active optical cable only) supports diagnostic functions via the Host complex.	**PASS**

Comments on Test Procedure
The test was completed with the standard procedure.

Comments on Test Results
Part A: The MUT/CUT supports diagnostic monitoring and the diagnostic information from the EEPROM was readable by the NOS.

Additional Comments

Test Information	Test Result
Test 6.1: **Establish Baseline Performance Analysis** *Purpose*: To establish a baseline performance analysis of the HUT.	**PASS**
Comments on Test Procedure	
This test was completed using a modified procedure. Because of a lack of 40G Golden Modules, the Host was baselined using each 40G MUT/CUT.	
Comments on Test Results	
The baseline performance of the Host was determined to be 90% line rate. All proceeding tests in Group 6 were conducted using this line rate.	
Additional Comments	

Test Information	Test Result
Test 6.2: **Detection on Power Up** *Purpose*: To determine if the MUT/CUT, HUT and LP establish a link while varying the power up sequence.	**PASS**
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
Part A: The Host and Link Partner were able to establish a valid link with this MUT/CUT while fully powered and operational. **Part B:** The Host and Link Partner were able to establish a valid link with this MUT/CUT when the Link Partner was powered on after the Host. **Part C:** The Host and Link Partner were able to establish a valid link with this MUT/CUT when the Host was powered on after the Link Partner.	
Additional Comments	

Test Information	Test Result
Test 6.3:**Packet Error Rate Estimation** *Purpose*: To determine if a Host can exchange packets with a Module or Cable Assembly such that a bit error rate of 10^{-12} is achieved	**PASS**

Comments on Test Procedure
This test was completed using the standard procedure.

Comments on Test Results
Part A: All 247,000,000 frames transmitted by TS1 were received by TS2. **Part B:** All 10,506,539,320 frames transmitted by TS1 were received by TS2.

Additional Comments

Test Information	Test Result
Test 6.4: **Packet Loss/Stress Test** *Purpose*: To verify that no obvious buffer management problems occur when directing a large volume of traffic at the Host and Module/Cable Assembly combination.	**PASS**

Comments on Test Procedure
This test was completed using the standard procedure.

Comments on Test Results
Parts A-D: All 1,000,000,000 64-byte frames transmitted by TS1 were received by TS2. All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2.

Additional Comments

Appendix A: EEPROM Data

10Gtek   SFP/SFP+/SFP28 module
Part Number: AXS13-192-10   Serial Number: WTSLRHA0096
10Gtek___WTSLRHA0096_____EEPROMdecode_20180831161407.txt

SERIAL_ID Keys:
BR_MAX: 10300
BR_MIN: 10300
BR_NOMINAL: 10300
CABLE_SPEC: 0x0 0x0
CONNECTOR: 7
DATE_CODE: 171001
DIAGNOSTIC_MONITORING_TYPE: 104
ENCODING: 6
ENHANCED_OPTIONS: 0
EXT_IDENTIFIER: 4
IDENTIFIER: 3
LENGTH_50UM: 0
LENGTH_62_5UM: 0
LENGTH_OM3: 0
LENGTH_OM4_OR_CU: 0
LENGTH_SMF: 10000
LENGTH_SMF_KM: 10000
OPTIONS: 0x0 0x0
RATE_IDENTIFIER: 0
SFF_8472_COMPLIANCE: 8
TRANSCEIVER: 0x20 0x0 0x0 0x0 0x12 0x0 0x1 0xd5
TRANSCEIVER_EXT: 0
VENDOR_NAME: 10Gtek
VENDOR_OUI: 0x0 0x0 0x0
VENDOR_PN: AXS13-192-10
VENDOR_REV: V01
VENDOR_SN: WTSLRHA0096
WAVELENGTH: 1310

Vendor Specific: 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x0 0x

I2C Address A0h, bytes 0-127, in hex
0000x: 03040720 00000012 0001d506 67000a64
0010x: 00000000 31304774 656b2020 20202020
0020x: 20202020 00000000 41585331 332d3139
0030x: 322d3130 20202020 56303120 051e003e
0040x: 00000000 5754534c 52484130 30393620
0050x: 20202020 31373130 30312020 6800086e
0060x: 00000000 00000000 00000000 00000000

0070x: 00000000 00000000 00000000 00000000

I2C Address A2h, bytes 0-127, in hex
0000x: 4b00fb00 46000000 946f6d5f 90887148
0010x: afc81388 a6041d4c 3de809cf 312d0c5a
0020x: 3de80064 372d007d 00000000 00000000
0030x: 00000000 00000000 00000000 00000000
0040x: 00000000 3f800000 00000000 01000000
0050x: 01000000 01000000 01000000 0000003f
0060x: 1e95827e 3a8718bc 00010000 00000200
0070x: 00400000 00400000 00004000 00000000

Appendix B: Pluggable Module / Cable Electrical Data

Generated by Viavi 5800-100G

Optics Self-Test

Customer Name	--
Technician ID	--
Test Location	--
Work Order	--
Comments/Notes	--

Overall Test Result: Pass

Appendix C: Host Electrical Data